

# FDP090N10

# N-Channel PowerTrench<sup>®</sup> MOSFET 100V, 75A, $9m\Omega$

### **Features**

- $R_{DS(on)} = 7.2 m\Omega$  ( Typ.) @  $V_{GS} = 10 V$ ,  $I_D = 75 A$
- · Fast switching speed
- · Low gate charge
- High performance trench technology for extremely low R<sub>DS(on)</sub>
- · High power and current handling capability
- · RoHS compliant

# **Application**

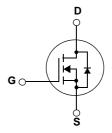
• DC to DC convertors / Synchronous Rectification



This N-Channel MOSFET is producedusing Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.







# MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol		Parameter		Ratings	Units
V <sub>DSS</sub>	Drain to Source Voltage			100	V
V <sub>GSS</sub>	Gate to Source Voltage			±20	V
I <sub>D</sub>	Drain Current	-Continuous (T <sub>C</sub> = 85°C)		75	Α
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	300	Α
E <sub>AS</sub>	Single Pulsed Avalanche I	Energy	(Note 2)	309	mJ
I <sub>AR</sub>	Avalance Current		(Note 1)	75	Α
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	20.8	mJ
dv/dt	Peak Diode Recovery dv/d	dt	(Note 3)	5.6	V/ns
Б	Davier Dissipation	$(T_C = 25^{\circ}C)$		208	W
$P_{D}$	Power Dissipation	- Derate above 25°C		1.39	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Te	mperature Range		-55 to +175	°C
T <sub>L</sub>	Maximum Lead Temperate 1/8" from Case for 5 Seco	• •		300	°C

# \*Drain current limited by maximum junction temperature

# **Thermal Characteristics**

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.72	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ. 0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient 62.5		

# Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity	
FDP090N10	FDP090N10	TO-220	=	=	50	

# **Electrical Characteristics**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250\mu A$ , $V_{GS} = 0V$ , $T_C = 25^{\circ}C$	100	-	-	V
ΔBV <sub>DSS</sub> ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.1	-	V/°C
1	Zana Cata Malta na Brain Commant	$V_{DS} = 100V, V_{GS} = 0V$	-	-	1	
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 100V, V_{GS} = 0V, T_{C} = 150^{\circ}C$	-	-	500	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA

# **On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.5	3.5	4.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 75A$	-	7.2	9	mΩ
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10V, I_D = 37.5A$ (Note 4)	-	100	ı	S

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05V V 0V	-	6185	8225	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz	-	585	775	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 = 11011 12	-	235	355	pF

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			-	107	224	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 50V, I_D = 75A$		-	322	655	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 25\Omega$		-	166	342	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4, 5)	-	149	309	ns
Q <sub>g(tot)</sub>	Total Gate Charge at 10V			-	89	116	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DS} = 50V, I_{D} = 75A$		-	37	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V	(Note 4, 5)	-	22	-	nC

## **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	75	Α	
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	300	Α	
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 75A		-	-	1.25	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 75A		-	73	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s $ (N	Note 4)	-	166	-	nC

- **Notes:**1. Repetitive Rating: Pulse width limited by maximum junction temperature 2: L = 0.11mH,  $I_{AS} = 75A$ ,  $V_{DD} = 50V$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^{\circ}C$  3:  $I_{SD} \le 75A$ , di/dt  $\le 200A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25^{\circ}C$  4: Pulse Test: Pulse width  $\le 300\mu s$ , Duty Cycle  $\le 2\%$  5: Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

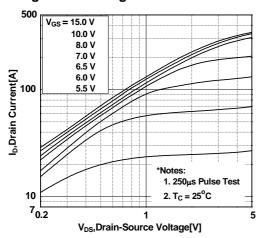


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

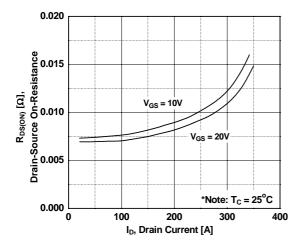


Figure 5. Capacitance Characteristics

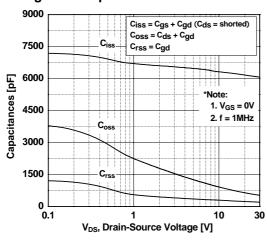


Figure 2. Transfer Characteristics

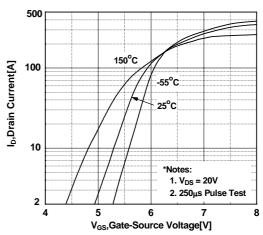


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

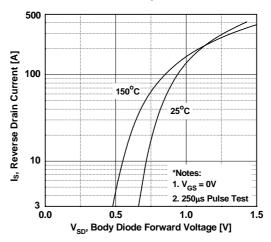
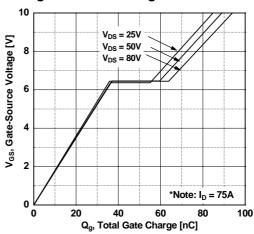


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

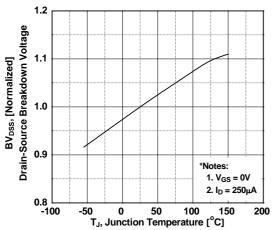


Figure 8. On-Resistance Variation vs. Temperature

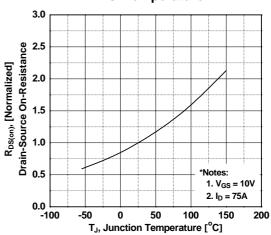


Figure 9. Maximum Safe Operating Area

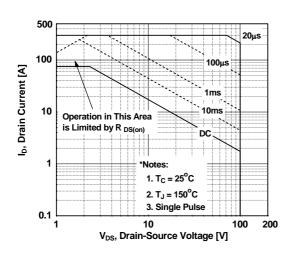


Figure 10. Maximum Drain Current vs. Case Temperature

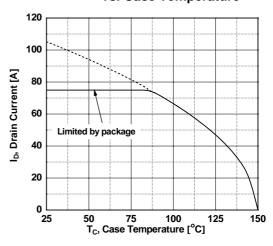
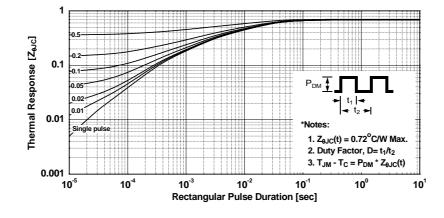
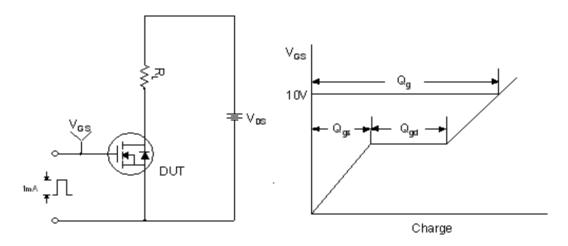


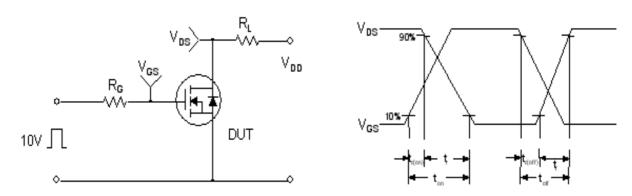
Figure 11. Transient Thermal Response Curve



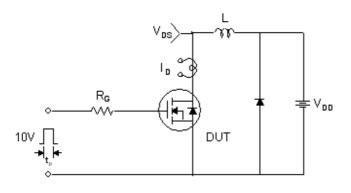
# **Gate Charge Test Circuit & Waveform**

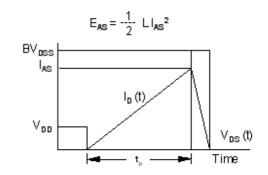


# **Resistive Switching Test Circuit & Waveforms**

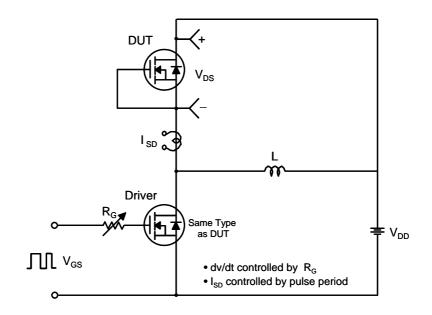


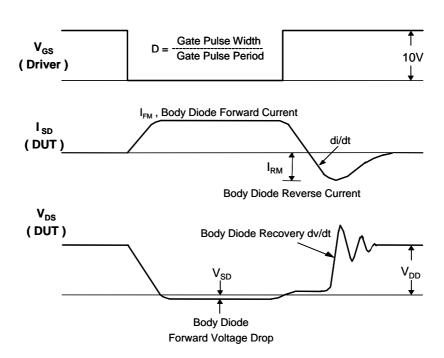
**Unclamped Inductive Switching Test Circuit & Waveforms** 





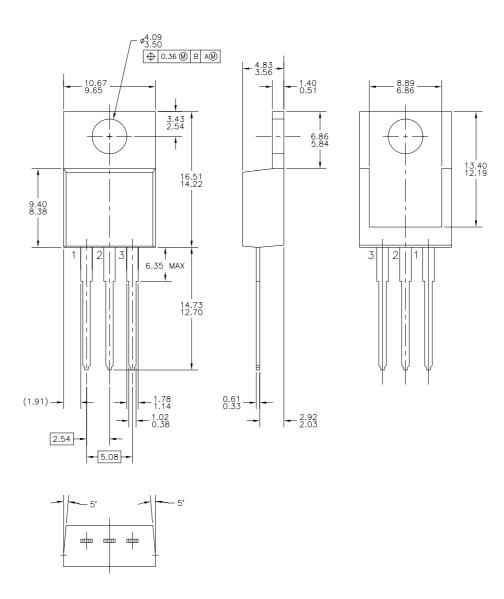
# Peak Diode Recovery dv/dt Test Circuit & Waveforms





# **Mechanical Dimensions**

# TO-220







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